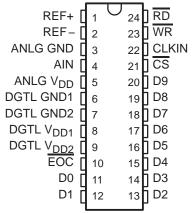
- Power Dissipation . . . 40 mW Max
- Advanced LinEPIC<sup>™</sup> Single-Poly Process Provides Close Capacitor Matching for Better Accuracy
- Fast Parallel Processing for DSP and μP Interface
- Either External or Internal Clock Can Be Used
- Conversion Time . . . 6 μs
- Total Unadjusted Error . . . ±1 LSB Max
- CMOS Technology

#### description

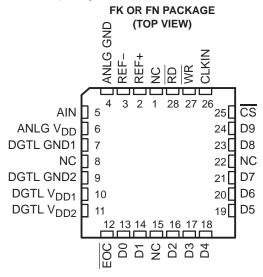
The TLC1550x and TLC1551 are data acquisition analog-to-digital converters (ADCs) using a 10-bit, switched-capacitor, successive-approximation network. A high-speed, 3-state parallel port directly interfaces to a digital signal processor (DSP) or microprocessor ( $\mu$ P) system data bus. D0 through D9 are the digital output terminals with D0 being the least significant bit (LSB). Separate power terminals for the analog and digital portions minimize noise pickup in the supply leads. Additionally, the digital power is divided into two parts to separate the lower current logic from the higher current bus drivers. An external clock can be applied to CLKIN to override the internal system clock if desired.

The TLC1550I and TLC1551I are characterized for operation from  $-40^{\circ}$ C to 85°C. The TLC1550M is characterized over the full military range of  $-55^{\circ}$ C to 125°C.

## J<sup>†</sup> OR DW PACKAGE (TOP VIEW)



† Refer to the mechanical data for the JW package.



NC - No internal connection

#### **AVAILABLE OPTIONS**

TA	PACKAGE							
	CERAMIC CHIP CARRIER (FK)	PLASTIC CHIP CARRIER (FN)	CERAMIC DIP (J)	SOIC (DW)				
-40°C to 85°C	_	TLC1550IFN TLC1551IFN	_	TLC1550IDW TLC1551IDW				
-55°C to 125°C	TLC1550MFK	_	TLC1550MJ	_				



This device contains circuits to protect its inputs and outputs against damage due to high static voltages or electrostatic fields. These circuits have been qualified to protect this device against electrostatic discharges (ESD) of up to 2 kV according to MIL-STD-883C, Method 3015; however, it is advised that precautions be taken to avoid application of any voltage higher than maximum-rated voltages to these high-impedance circuits. During storage or handling, the device leads should be shorted together or the device should be placed in conductive foam. In a circuit, unused inputs should always be connected to an appropriated logic voltage level, preferably either V<sub>CC</sub> or ground.



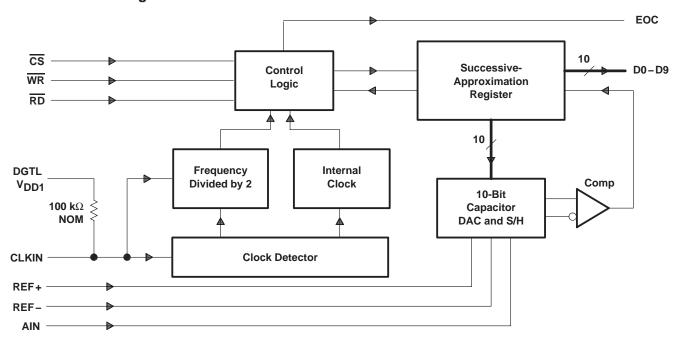
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

Advanced LinEPIC is a trademark of Texas Instruments.



SLAS043G - MAY 1991 - REVISED NOVEMBER 2003

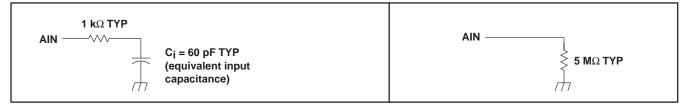
#### functional block diagram



### typical equivalent inputs

#### INPUT CIRCUIT IMPEDANCE DURING SAMPLING MODE

#### INPUT CIRCUIT IMPEDANCE DURING HOLD MODE



### **Terminal Functions**

TERMINAL								
NAME	NO.†	NO.‡	DESCRIPTION					
ANLG GND	4	3	Analog ground. The reference point for the voltage applied on terminals ANLG V <sub>DD</sub> , AIN, REF+, and REF					
AIN	5	4	Analog voltage input. The voltage applied to AIN is converted to the equivalent digital output.					
ANLG V <sub>DD</sub>	6	5	Analog positive power supply voltage. The voltage applied to this terminal is designated V <sub>DD3</sub> .					
CLKIN	26	22	Clock input. CLKIN is used for external clocking instead of using the internal system clock. It usually takes a few microseconds before the internal clock is disabled. To use the internal clock, CLKIN should be tied high or left unconnected.					
CS	25	21	Chip-select. CS must be low for RD or WR to be recognized by the A/D converter.					
D0	13	11	Data bus output. D0 is bit 1 (LSB).					
D1	14	12	Data bus output. D1 is bit 2.					
D2	16	13	Data bus output. D2 is bit 3.					
D3	17	14	Data bus output. D3 is bit 4.					
D4	18	15	Data bus output. D4 is bit 5.					
D5	19	16	Data bus output. D5 is bit 6.					
D6	20	17	Data bus output. D6 is bit 7.					
D7	21	18	Data bus output. D7 is bit 8.					
D8	23	19	Data bus output. D8 is bit 9.					
D9	24	20	Data bus output. D9 is bit 10 (MSB).					
DGTL GND1	7	6	Digital ground 1. The ground for power supply DGTL V <sub>DD1</sub> and is the substrate connection					
DGTL GND2	9	7	Digital ground 2. The ground for power supply DGTL V <sub>DD2</sub>					
DGTL V <sub>DD1</sub>	10	8	Digital positive power-supply voltage 1. DGTL V <sub>DD1</sub> supplies the logic. The voltage applied to DGTL V <sub>DD1</sub> is designated V <sub>DD1</sub> .					
DGTL V <sub>DD2</sub>	11	9	Digital positive power-supply voltage 2. DGTL V <sub>DD2</sub> supplies only the higher-current output buffers. The voltage applied to DGTL V <sub>DD2</sub> is designated V <sub>DD2</sub> .					
EOC	12	10	End-of-conversion. $\overline{EOC}$ goes low indicating that conversion is complete and the results have been transferred to the output latch. $\overline{EOC}$ can be connected to the $\mu P$ - or DSP-interrupt terminal or can be continuously polled.					
RD	28	24	Read input. When $\overline{\text{CS}}$ is low and $\overline{\text{RD}}$ is taken low, the data is placed on the data bus from the output latch. The output latch stores the conversion results at the most recent negative edge of $\overline{\text{EOC}}$ . The falling edge of $\overline{\text{RD}}$ resets $\overline{\text{EOC}}$ to a high within the $t_{d}(\overline{\text{EOC}})$ specifications.					
REF+	2	1	Positive voltage-reference input. Any analog input that is greater than or equal to the voltage on REF+ converts to 1111111111. Analog input voltages between REF+ and REF – convert to the appropriate result in a ratiometric manner.					
REF-	3	2	Negative voltage reference input. Any analog input that is less than or equal to the voltage on REF – converts to 0000000000.					
WR	27	23	Write input. When $\overline{\text{CS}}$ is low, conversion is started on the rising edge of $\overline{\text{WR}}$ . On this rising edge, the ADC holds the analog input until conversion is completed. Before and after the conversion period, which is given by $t_{\text{CONV}_1}$ the ADC remains in the sampling mode.					



<sup>†</sup> Terminal numbers for FK and FN packages. ‡ Terminal numbers for J, DW, and NW packages.

SLAS043G - MAY 1991 - REVISED NOVEMBER 2003

# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>DD1</sub> , V <sub>DD2</sub> , and V <sub>DD3</sub> (see Note 1)	6.5 V
Input voltage range, V <sub>I</sub> (any input)	$-0.3 \text{ V to V}_{DD} + 0.3 \text{ V}$
Output voltage range, V <sub>O</sub>	$-0.3 \text{ V to V}_{DD} + 0.3 \text{ V}$
Peak input current (any digital input)	±10 mA
Peak total input current (all inputs)	±30 mA
Operating free-air temperature range, T <sub>A</sub> : TLC1550I, TLC1551I	40°C to 85°C
TLC1550M	55°C to 125°C
Storage temperature range, T <sub>stq</sub>	65°C to 150°C
Case temperature for 10 seconds: FK or FN package	
Lead temperature 1,6 mm (1/16 inch) from the case for 10 seconds: J or NW package	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		MIN	NOM	MAX	UNIT	
Supply voltage, V <sub>DD1</sub> , V <sub>DD2</sub> , V <sub>DD3</sub>	4.75	5	5.5	V		
Positive reference voltage, V <sub>REF+</sub> (see Note 2)			V <sub>DD3</sub>		V	
Negative reference voltage, V <sub>REF</sub> (see Note 2)			0		V	
Differential reference voltage, V <sub>REF+</sub> – V <sub>REF-</sub> (see Note 2)				V <sub>DD3</sub>	V	
Analog input voltage range		0		V <sub>DD3</sub>	V	
High-level control input voltage, VIH		2			V	
Low-level control input voltage, V <sub>IL</sub>			0.8	V		
Input clock frequency, f(CLKIN)	0.5		7.8	MHz		
Setup time, CS low before WR or RD goes low, t <sub>SU(CS)</sub>		0			ns	
Hold time, CS low after WR or RD goes high, th(CS)		0			ns	
WR or RD pulse duration, t <sub>W(WR)</sub>		50			ns	
Input clock low pulse duration, t <sub>W</sub> (L-CLKIN)		40% of period		80% of period		
On another two air to an another T.	TLC155xl	-40		85		
Operating free-air temperature, T <sub>A</sub>	TLC1550M	-55		125	•C	

NOTE 2: Analog input voltages greater than that applied to REF+ convert to all 1s (1111111111), while input voltages less than that applied to REF- convert to all 0s (0000000000). The total unadjusted error may increase as this differential voltage falls below 4.75 V.



NOTE 1: V<sub>DD1</sub> is the voltage measured at DGTL V<sub>DD1</sub> with respect to DGND1. V<sub>DD2</sub> is the voltage measured at DGTL V<sub>DD2</sub> with respect to the DGND2. V<sub>DD3</sub> is the voltage measured at ANLG V<sub>DD</sub> with respect to AGND. For these specifications, all ground terminals are tied together (and represent 0 V). When V<sub>DD1</sub>, V<sub>DD2</sub>, and V<sub>DD3</sub> are equal, they are referred to simply as V<sub>DD</sub>.

SLAS043G - MAY 1991 - REVISED NOVEMBER 2003

# electrical characteristics over recommended operating free-air temperature range, $V_{DD} = V_{REF+} = 4.75 \text{ V}$ to 5.5 V and $V_{REF-} = 0$ (unless otherwise noted)

PARAMETER			TES1	TEST CONDITIONS			MAX	UNIT
Vон	High-level output voltage		V <sub>DD</sub> = 4.75 V,	I <sub>OH</sub> = -360 μA	2.4			V
V	Lave lavel autout valtage		V <sub>DD</sub> = 4.75 V,	T <sub>A</sub> = 25°C			0.4	.,
VOL	Low-level output voltage		$I_{OL} = 2.4 \text{ mA}$	$T_A = -55^{\circ}C \text{ to } 125^{\circ}C$			0.5	V
		$V_O = V_{DD}$	CS and RD at V <sub>DD</sub>			10		
loz	Off-state (high-impedance-sta	mpedance-state) output current		CS and RD at V <sub>DD</sub>			-10	μΑ
I <sub>IH</sub> High-level input current			$V_I = V_{DD}$			0.005	2.5	μΑ
Ι <sub>Ι</sub> L	I <sub>IL</sub> Low-level input current (except CLKIN)				-2.5	-0.005		μΑ
Ι <sub>Ι</sub> L	Low-level input current (CLKI			-50	-50		μΑ	
			V <sub>O</sub> = 5 V,	T <sub>A</sub> = 25°C	7	14		
los	Short-circuit output current		$V_{O} = 0$ ,	T <sub>A</sub> = 25°C		-12	-6	mA
I <sub>(DD)</sub>	Operating supply current		CS low and RD	high		2	8	mA
,	Innut conscitones	Analog inputs	Coo turnical actu	See typical equivalent inputs TLC1550/1I		60	90*	pF
	Input capacitance	Digital inputs	See typical equ			5	15*	

 $<sup>\</sup>ensuremath{^{\star}}$  On products compliant to MIL-STD-883, Class B, this parameter is not production tested.

<sup>†</sup> All typical values are at  $V_{DD} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

SLAS043G - MAY 1991 - REVISED NOVEMBER 2003

operating characteristics over recommended operating free-air temperature range with internal clock and minimum sampling time of 4  $\mu$ s,  $V_{DD} = V_{REF+} = 5$  V and  $V_{REF-} = 0$  (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	T <sub>A</sub> †	MIN	TYP‡	MAX	UNIT	
		TLC1550I		Full range			±0.5	LSB	
_		TLC1551I		Full range			±1		
EL	Linearity error	TI 04550M	See Note 3	25°C			±0.5		
		TLC1550M		Full range			±1		
		TLC1550I		Full range			±0.5		
		TLC1551I		Full range			±1	LSB	
EZS	Zero-scale error	TI 0455014	See Notes 2 and 4	25°C			±0.5		
		TLC1550M		Full range			±1		
		TLC1550I		Full range			±0.5	LSB	
_	Full-scale error	TLC1551I	7	Full range			±1		
EFS		TLC1550M	See Notes 2 and 4	25°C			±0.5		
				Full range			±1		
		TLC1550I		Full range			±0.5	LSB	
	Total unadjusted error	TLC1551I	See Note 5	Full range			±1		
		TLC1550M		25°C			±1		
t <sub>C</sub>	Conversion time		fclock(external) = 4.2 MHz or internal clock				6	μs	
ta(D)	Data access time after RD goes low						35	ns	
t <sub>V</sub> (D)	Data valid time after RD goes high  Disable time, delay time from RD high to high impedance		7		5			ns	
t <sub>dis(D)</sub>			See Figure 3				30	ns	
t <sub>d</sub> (EOC)	Delay time, RD low to EOC hi	gh			0	15		ns	

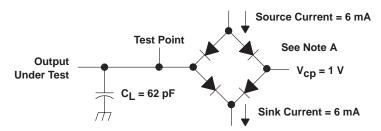
<sup>†</sup> Full range is  $-40^{\circ}$ C to  $85^{\circ}$ C for the TL155xI devices and  $-55^{\circ}$ C to  $125^{\circ}$ C for the TLC1550M.

- NOTES: 2. Analog input voltages greater than that applied to REF+ convert to all 1s (1111111111), while input voltages less than that applied to REF convert to all 0s (0000000000). The total unadjusted error may increase as this differential voltage falls below 4.75 V.
  - 3. Linearity error is the difference between the actual analog value at the transition between any two adjacent steps and its ideal value after zero-scale error and full-scale error have been removed.
  - 4. Zero-scale error is the difference between the actual mid-step value and the nominal mid-step value at specified zero scale. Full-scale error is the difference between the actual mid-step value and the nominal mid-step value at specified full scale.
  - 5. Total unadjusted error is the difference between the actual analog value at the transition between any two adjacent steps and its ideal value. It includes contributions from zero-scale error, full-scale error, and linearity error.



<sup>‡</sup> All typical values are at V<sub>DD</sub> = 5 V, T<sub>A</sub> = 25°C.

### PARAMETER MEASUREMENT INFORMATION



V<sub>cp</sub> = voltage commutation point for switching between source and sink currents

NOTE A: Equivalent load circuit of the Teradyne A500 tester for timing parameter measurement

Figure 1. Test Load Circuit

#### **APPLICATION INFORMATION**

#### simplified analog input analysis

Using the circuit in Figure 2, the time required to charge the analog input capacitance from 0 to  $V_S$  within 1/2 LSB can be derived as follows:

The capacitance charging voltage is given by

$$V_{C} = V_{S} \left( 1 - e^{-t_{C}/R_{t}C_{i}} \right)$$
 (1)

Where:

$$R_t = R_s + r_i$$

The final voltage to 1/2 LSB is given by

$$V_C (1/2 LSB) = V_S - (V_S/1024)$$
 (2)

Equating equation 1 to equation 2 and solving for time t<sub>c</sub> gives

$$V_{S} - \left(V_{S}/512\right) = V_{S}\left(1 - e^{-t_{C}/R_{t}C_{i}}\right)$$
(3)

and

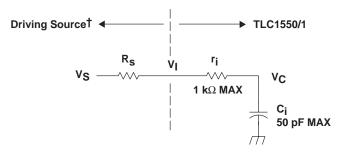
$$t_{C} (1/2 LSB) = R_{t} \times C_{j} \times ln(1024)$$

$$\tag{4}$$

Therefore, with the values given, the time for the analog input signal to settle is

$$t_{\rm C} (1/2 \text{ LSB}) = (R_{\rm S} + 1 \text{ k}\Omega) \times 60 \text{ pF} \times \ln(1024)$$
 (5)

This time must be less than the converter sample time shown in the timing diagrams.



V<sub>I</sub> = Input voltage at AIN

V<sub>S</sub> = External driving source voltage

R<sub>S</sub> = Source resistance

r<sub>i</sub> = Input resistance

C<sub>i</sub> = Input capacitance

† Driving source requirements:

- Noise and distortion for the source must be equivalent to the resolution of the converter.
- R<sub>S</sub> must be real at the input frequency.

Figure 2. Input Circuit Including the Driving Source



#### PRINCIPLES OF OPERATION

The operating sequence for complete data acquisition is shown in Figure 3. Processors can address the TLC1550 and TLC1551 as an external memory device by simply connecting the address lines to a decoder and the decoder output to  $\overline{CS}$ . Like other peripheral devices, the write ( $\overline{WR}$ ) and read ( $\overline{RD}$ ) input signals are valid only when  $\overline{CS}$  is low. Once  $\overline{CS}$  is low, the onboard system clock permits the conversion to begin with a simple write command and the converted data to be presented to the data bus with a simple read command. The device remains in a sampling (track) mode from the rising edge of  $\overline{EOC}$  until conversion begins with the rising edge of  $\overline{WR}$ , which initiates the hold mode. After the hold mode begins, the clock controls the conversion automatically. When the conversion is complete, the end-of-conversion ( $\overline{EOC}$ ) signal goes low indicating that the digital data has been transferred to the output latch. Lowering  $\overline{CS}$  and  $\overline{RD}$  then resets  $\overline{EOC}$  and transfers the data to the data bus for the processor read cycle.

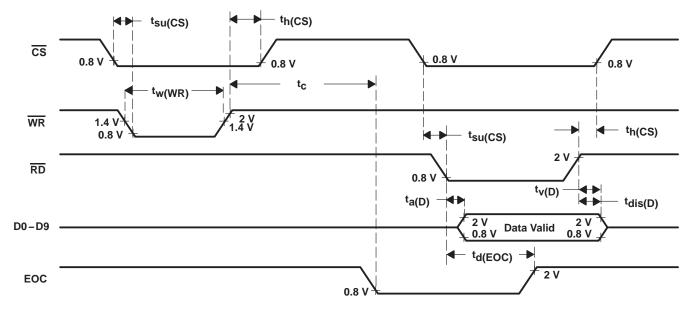


Figure 3. TLC1550 or TLC1551 Operating Sequence









#### **PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
TLC1550IDW	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1550IDWG4	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1550IDWR	ACTIVE	SOIC	DW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1550IDWRG4	ACTIVE	SOIC	DW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1550IFN	ACTIVE	PLCC	FN	28	37	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1550IFNR	ACTIVE	PLCC	FN	28	750	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1550INW	OBSOLETE	PDIP	NW	24		TBD	Call TI	Call TI
TLC1550MFKB	OBSOLETE	LCCC	FK	28		TBD	Call TI	Call TI
TLC1550MJ	OBSOLETE	CDIP	J	24		TBD	Call TI	Call TI
TLC1550MJB	OBSOLETE	CDIP	J	24		TBD	Call TI	Call TI
TLC1551IDW	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1551IDWG4	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1551IDWR	ACTIVE	SOIC	DW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1551IDWRG4	ACTIVE	SOIC	DW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1551IFN	ACTIVE	PLCC	FN	28	37	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLC1551IFNG4	ACTIVE	PLCC	FN	28	37	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



#### PACKAGE OPTION ADDENDUM

16-Mar-2007

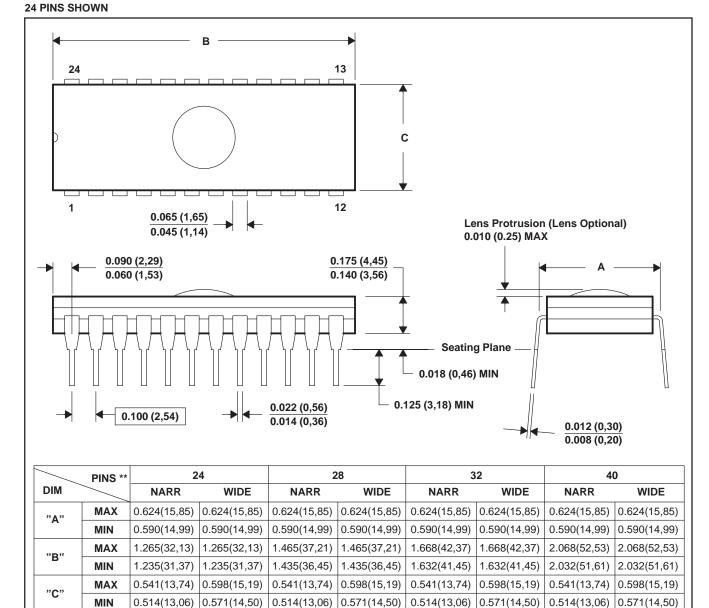
Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

4040084/C 10/97

#### J (R-GDIP-T\*\*)

#### **CERAMIC DUAL-IN-LINE PACKAGE**



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Window (lens) added to this group of packages (24-, 28-, 32-, 40-pin).
- D. This package can be hermetically sealed with a ceramic lid using glass frit.
- E. Index point is provided on cap for terminal identification.



#### FK (S-CQCC-N\*\*)

#### **28 TERMINAL SHOWN**

#### **LEADLESS CERAMIC CHIP CARRIER**



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a metal lid.
- D. The terminals are gold plated.
- E. Falls within JEDEC MS-004



# DW (R-PDSO-G24)

# PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



#### FN (S-PQCC-J\*\*)

#### 20 PIN SHOWN

#### PLASTIC J-LEADED CHIP CARRIER



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-018



#### IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Interface	interface.ti.com	Digital Control	www.ti.com/digitalcontrol
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
Low Power Wireless	www.ti.com/lpw	Telephony	www.ti.com/telephony
		Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments

Post Office Box 655303 Dallas, Texas 75265